

- 1. Status of the VME based DAQ for the Hjet***
- 2. Evaluation of the Hjet time resolution.***

VME Based DAQ for the HJet

Current Status

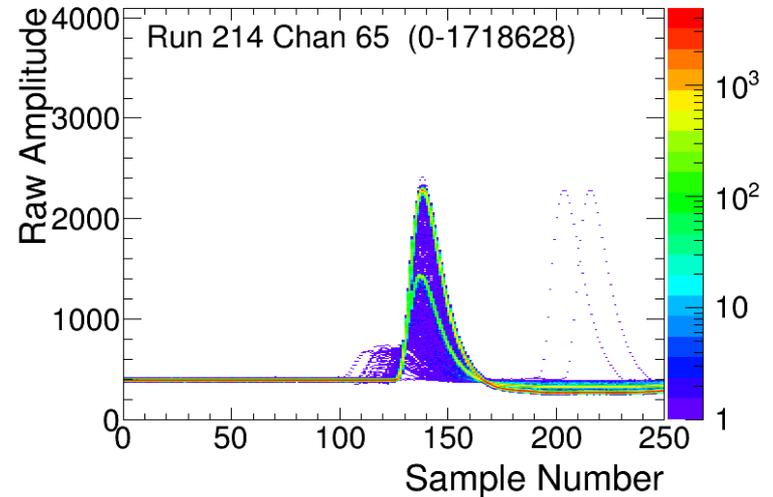
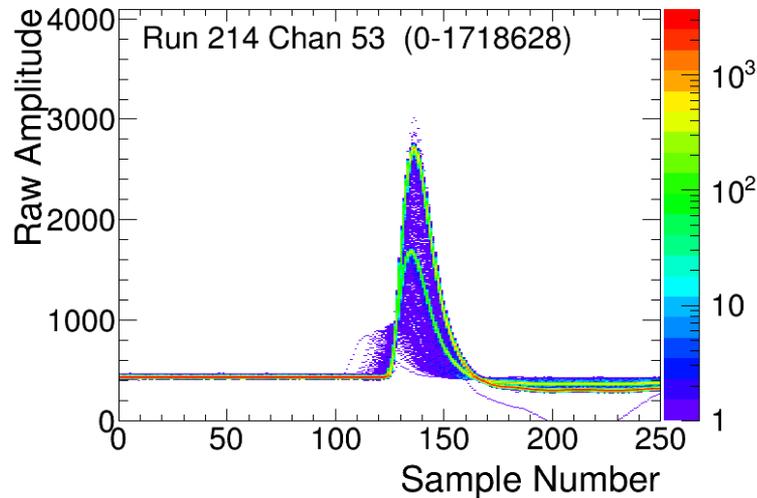
- *A Prototype is assembled in the Counting Room (Bldg. 1012)*
- *Alpha source signals in are intensively tested*
- *Wiener VME Crate was arived but not installed yet.*
- ***We still have no internal trigger.***
- *DAQ software still need work.*

Know Issues

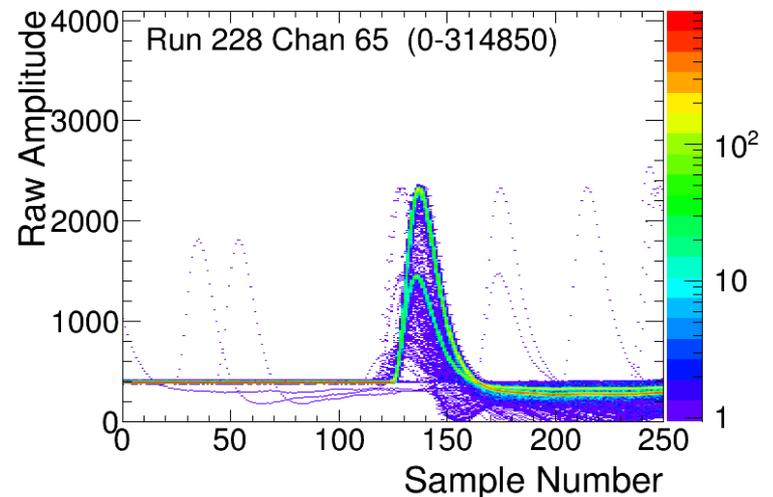
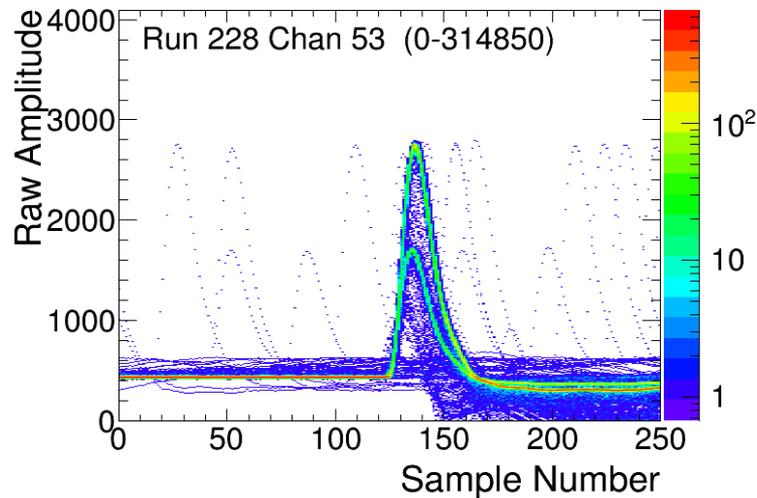
- *Det. 8 (Ch. 84-95) - Split Gain (permanently)*
Energy resolution 20 keV -> 35 keV (Am)
20 keV -> 25 keV (Gd)
- *Det. 5-6 (Ch. 48-71) - Overshoot oscillations (episodically)*
- *Det. 4 (Ch, 36-47) - Ringing (episodically)*
- *All detectors (simultaneously) – unstable waveform (episodically)*
Neither issue is critical for running,
but these are indication of possible instability

Detectors 5-6 (Ch. 48-71): High Rate Trigger

Good State:

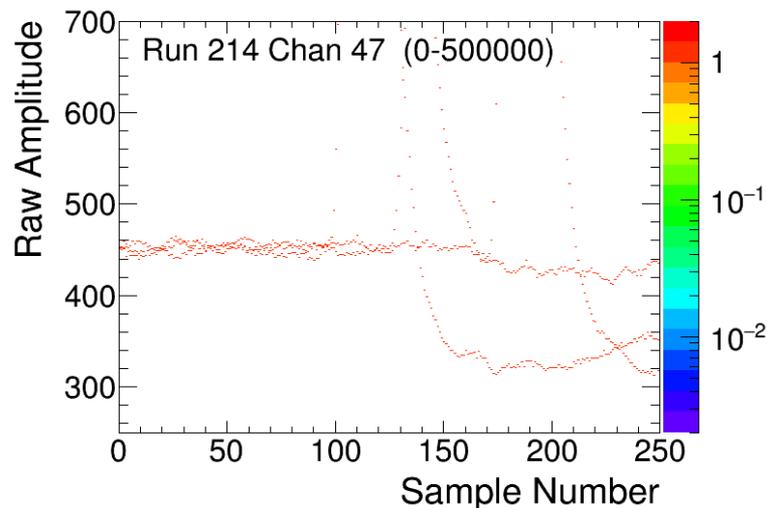
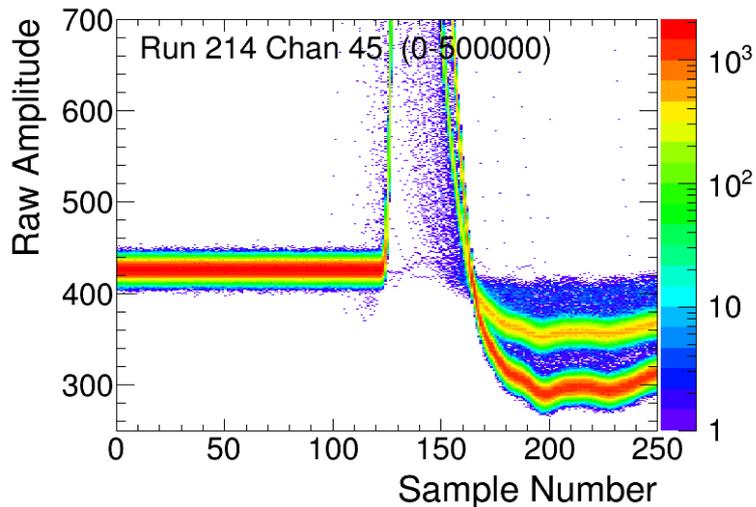


High Rate Trigger (Trigger is discriminated before shaping):

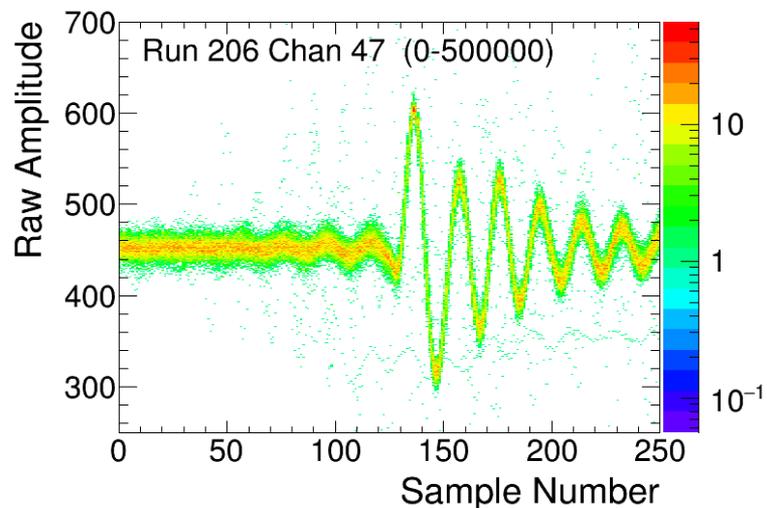
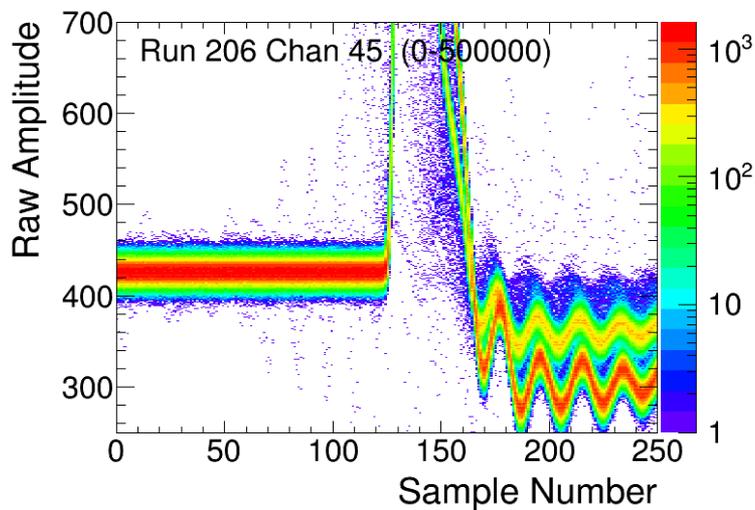


Detector 4 (Ch. 36-47): Ringing

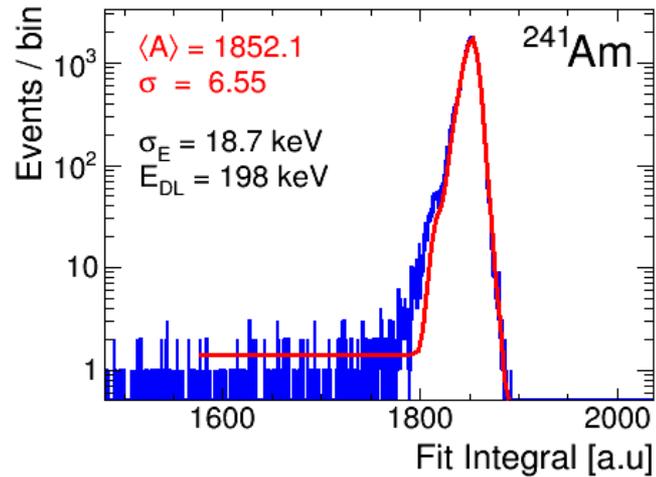
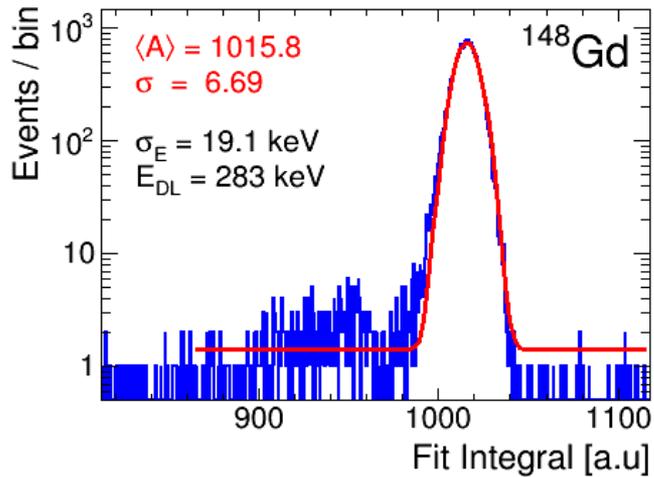
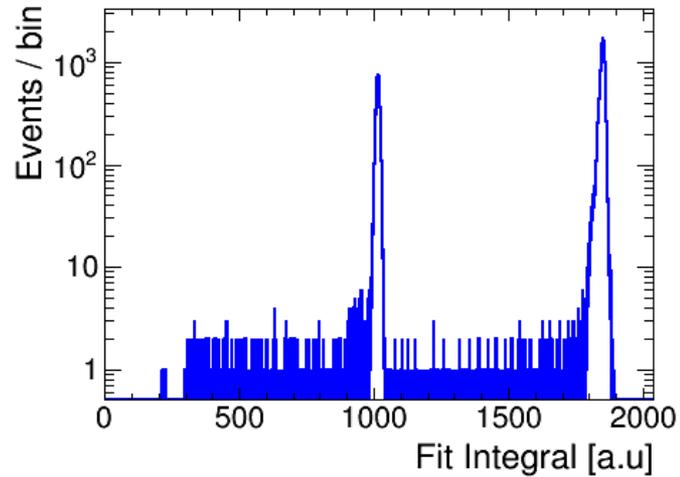
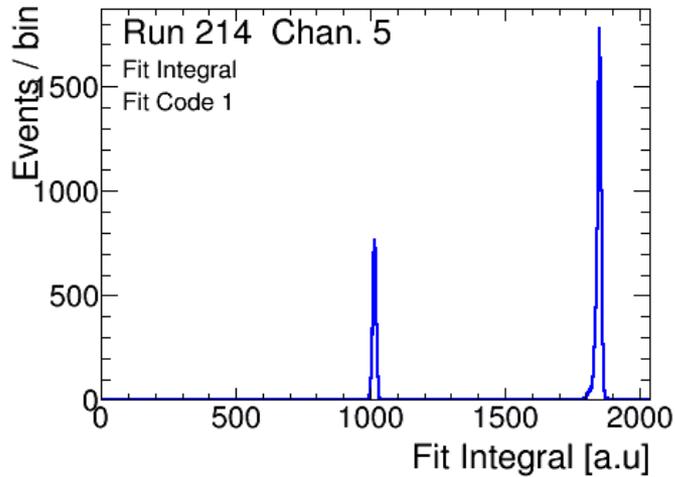
Good State:



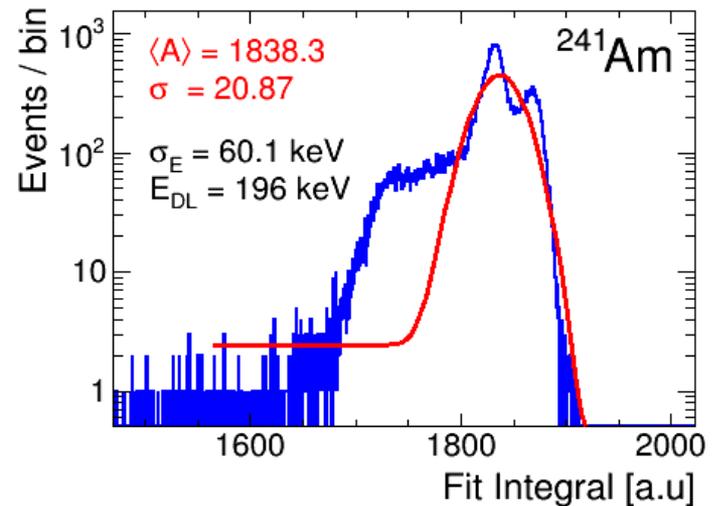
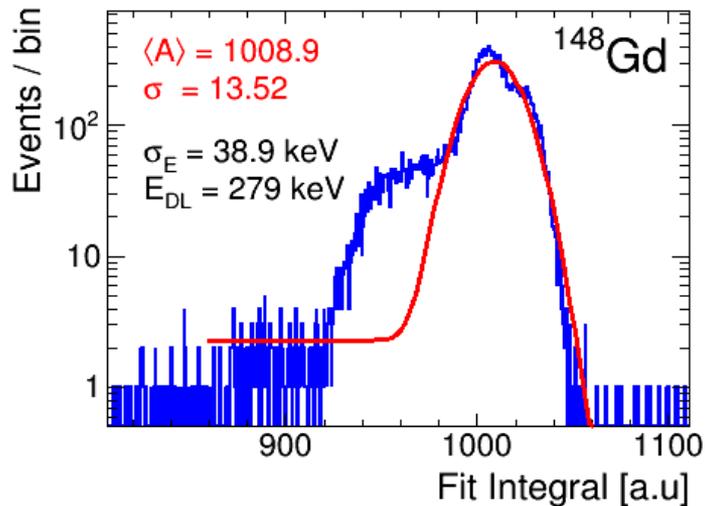
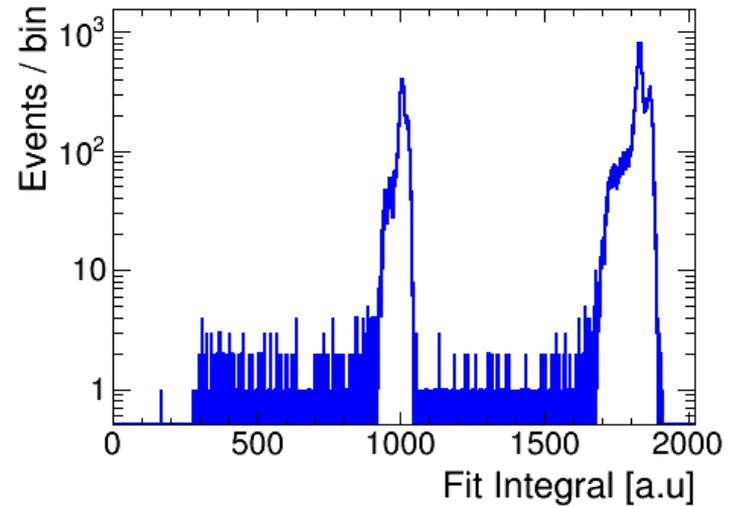
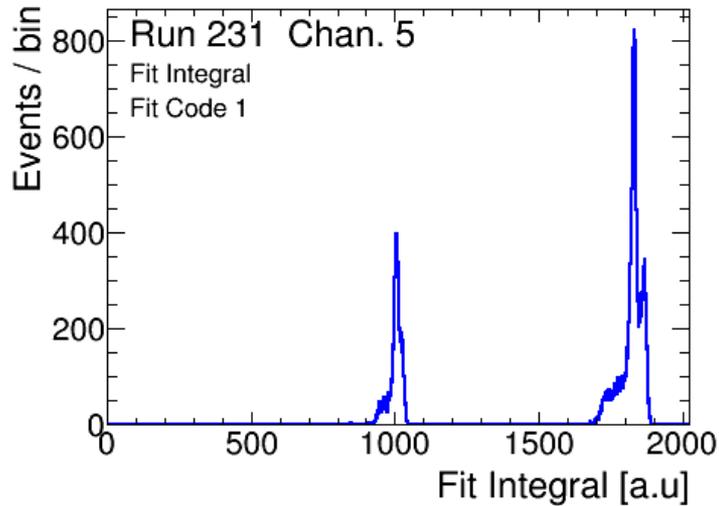
Ringing State:



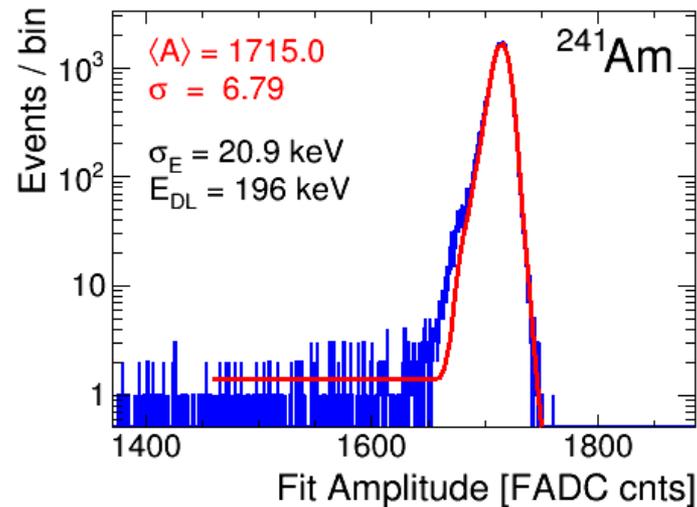
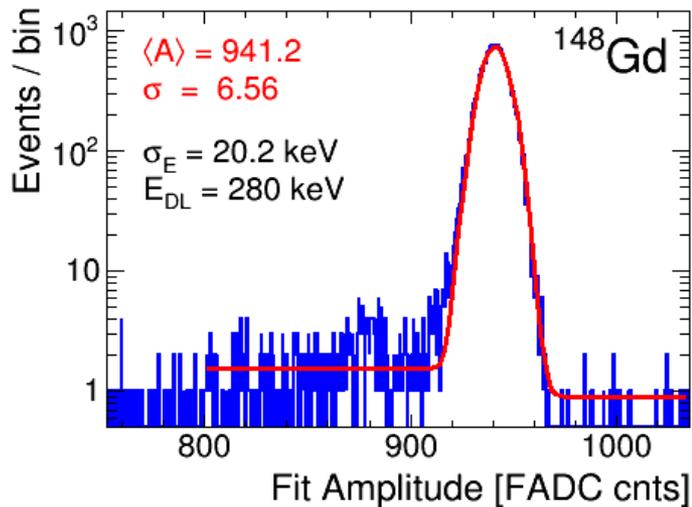
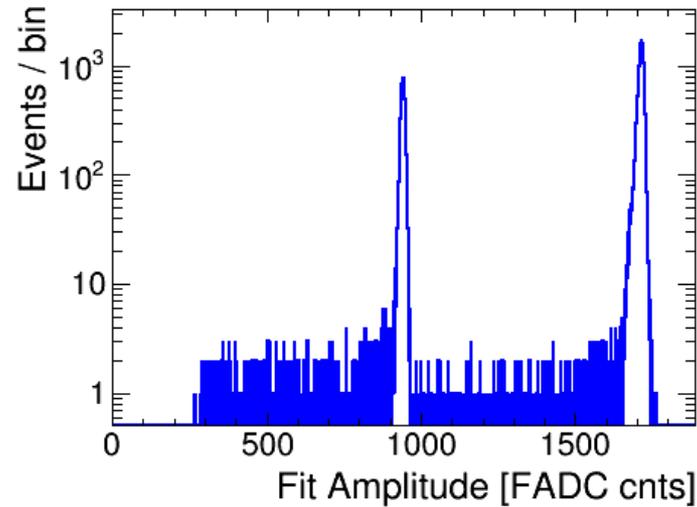
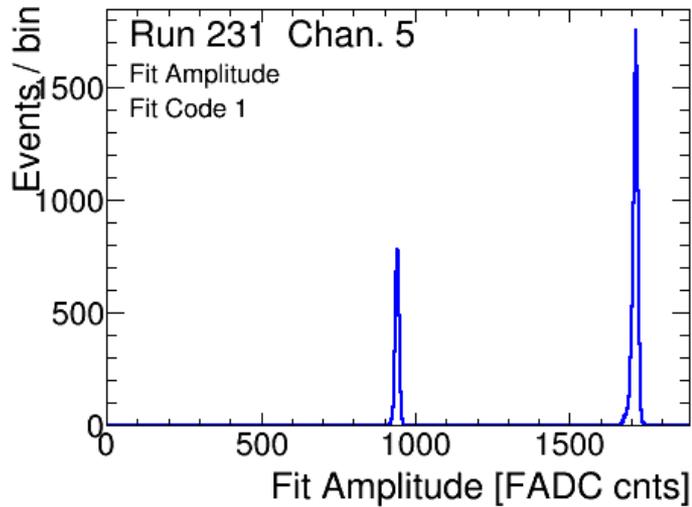
Unstable waveform. *Run 214. Integral*



Unstable waveform. *Run 231 Integral*



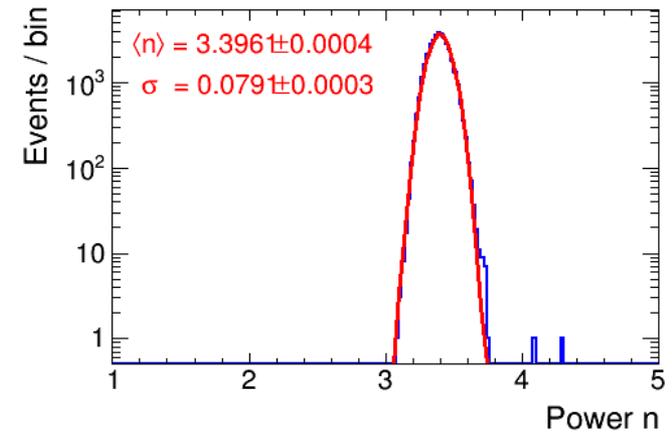
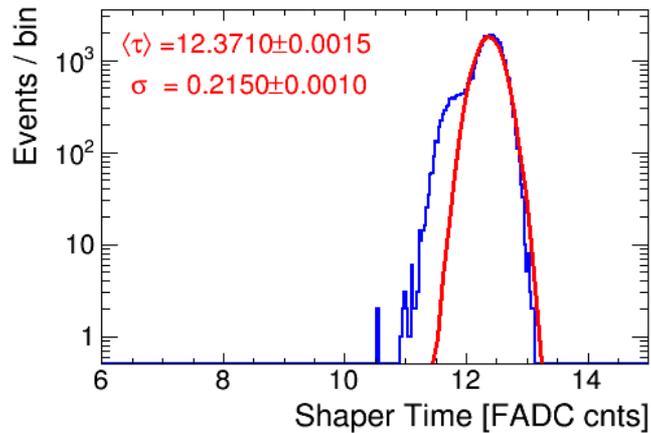
Unstable waveform. *Run 231 Amplitude*



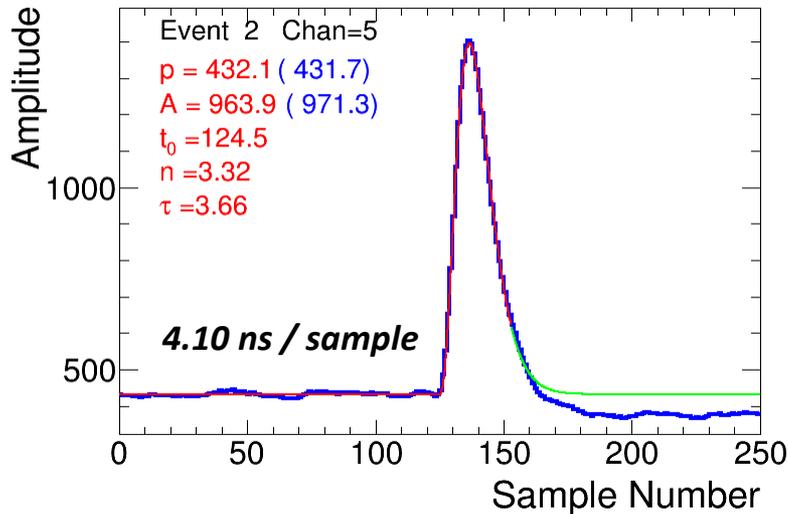
Unstable waveform. Comments.

- Gain instability is seen only in Integral: $I = A \tau I_n$
- Instability of measurements may be related to instability of τ or n
- Usually the τ is very stable
- In Run 231 is associated with time scale (e.g. clock stability)

Run 231. Ch. 5



A typical waveform: 3.183 keV α (^{148}Gd)



— measured waveform
 — fit function $W(t)$
 — continuation of the fit function

Parameterization:

- p - pedestal
- A - amplitude
- t_0 - signal time
- n - shaper power
- τ - shaper time

Signal parametrization:

$$A(t) \sim (t - t_0)^n \exp\left(-\frac{t - t_0}{\tau/n}\right)$$

Waveform parametrization:

$$W(t) = p + Af_n(\xi), \quad \xi = \frac{t - t_0}{\tau}$$

$$f_n(\xi) = e^{n(1 + \log \xi - \xi)}$$

$$0 \leq f_n(\xi) \leq f_n(1) = 1$$

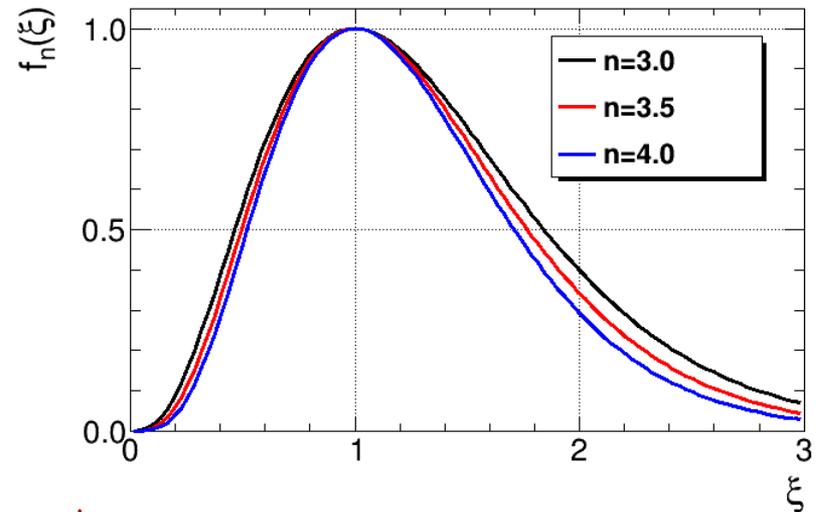
$$I = \int_{t_0}^{\infty} A(t) dt = A\tau I_n$$

$$I_n = e^{n(1 - \log n)} \Gamma(n) \quad \Gamma(n) = \int_0^{\infty} x^{n-1} e^{-x} dx$$

Understanding of the fit function

$$W(t) = p + Af_n(\xi), \quad \xi = \frac{t - t_0}{\tau}$$

- p , A , t_0 , and τ define linear transformation of the $f_n(t)$
- n is the only parameter which define the waveform shape.



$$t_m = t_0 + \tau$$

Errors in the fit (due to noise) may be approximated by:

$$\langle \delta_{t_0}^2 \rangle^{1/2} = \langle \delta_{t_m}^2 \rangle^{1/2} \oplus \langle \delta_{\tau}^2 \rangle^{1/2}$$

Time resolution may be evaluated as:

$$t_0 \rightarrow \sigma_t = \langle \delta_{t_m}^2 \rangle^{1/2} \oplus \langle \delta_{\tau}^2 \rangle^{1/2}$$

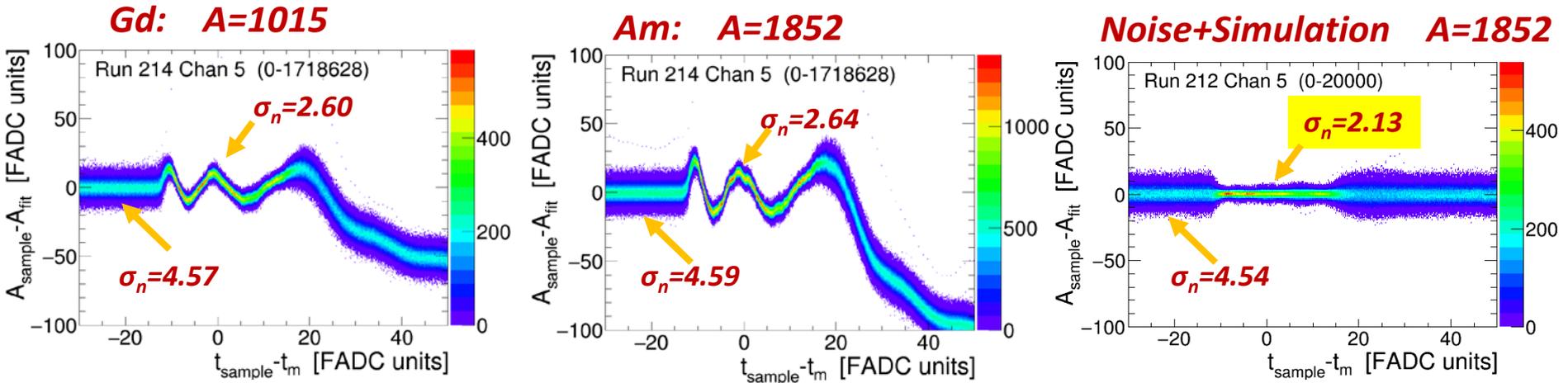
$$t_m \rightarrow \sigma_t = \langle \delta_{t_m}^2 \rangle^{1/2} \oplus \sigma_{\tau}$$

Fluctuations of the τ

Experimental estimates for ^{241}Am signal:

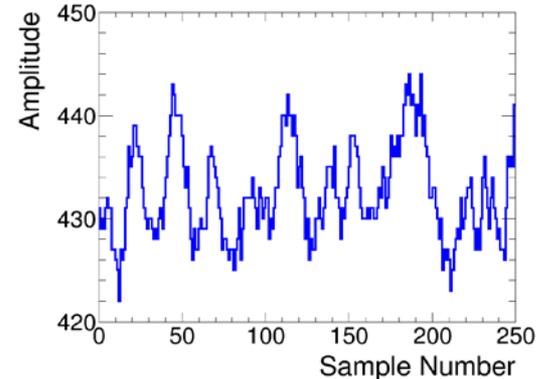
$$\langle \delta_{t_m}^2 \rangle^{1/2} \approx 100 \text{ ps} \quad \langle \delta_{\tau}^2 \rangle^{1/2} \sim 400 \text{ ps} \quad \sigma_{\tau} < 80 \text{ ps}$$

Quality of the Parametrization



- **Measured waveform systematically differs ($\sim 2\%$) from the simulated one.**
- **This must not be an issue for the measurements**
- **In addition to electronic noise, there are fluctuations of the waveform shapes**

Typical noise:

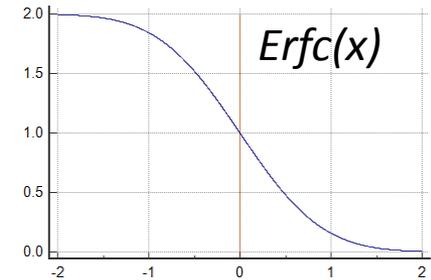


How to measure time resolution (relative to external trigger)

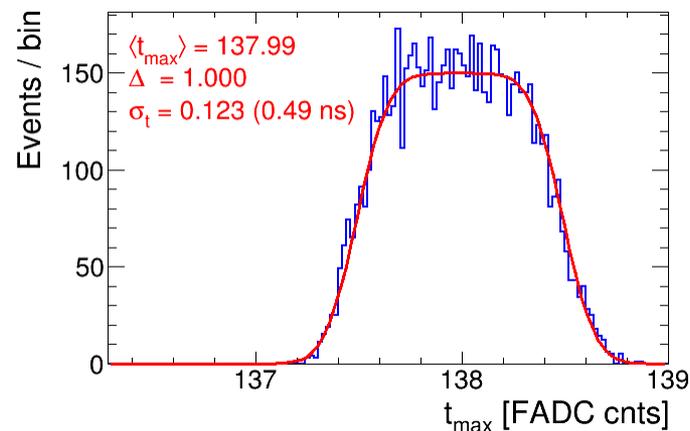
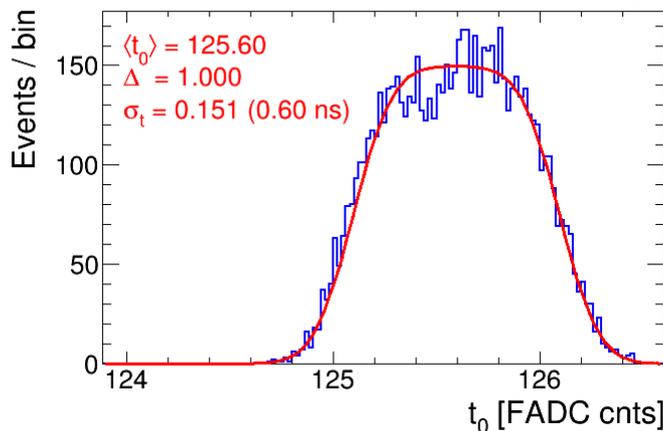
Since trigger is aligned to clock tick, the measured time distribution is non-gaussian.

$$f(t) = \int_{\langle t \rangle - \Delta/2}^{\langle t \rangle + \Delta/2} d\tilde{t} \exp\left(-\frac{(\tilde{t} - t)^2}{2\sigma^2}\right) \sim \text{Erfc}\left(\frac{t - \langle t \rangle - \Delta/2}{\sqrt{2}\sigma}\right) - \text{Erfc}\left(\frac{t - \langle t \rangle + \Delta/2}{\sqrt{2}\sigma}\right)$$

However, since the distribution is analytical function (to computer) we can determine σ from the fit.



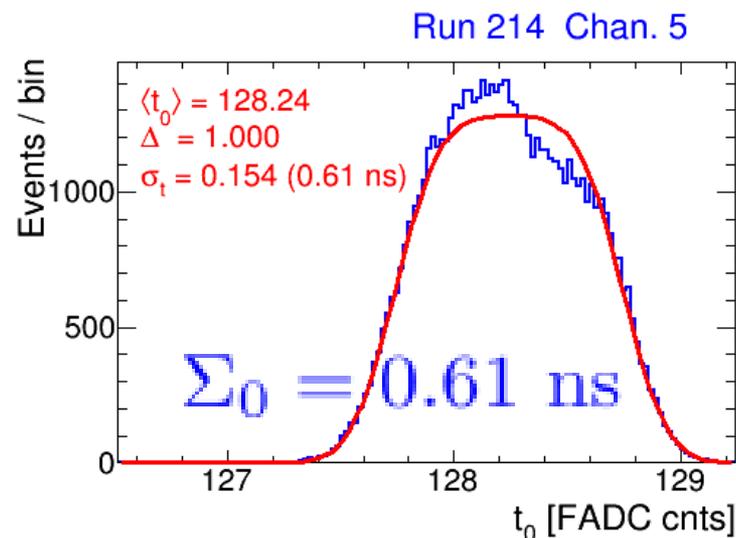
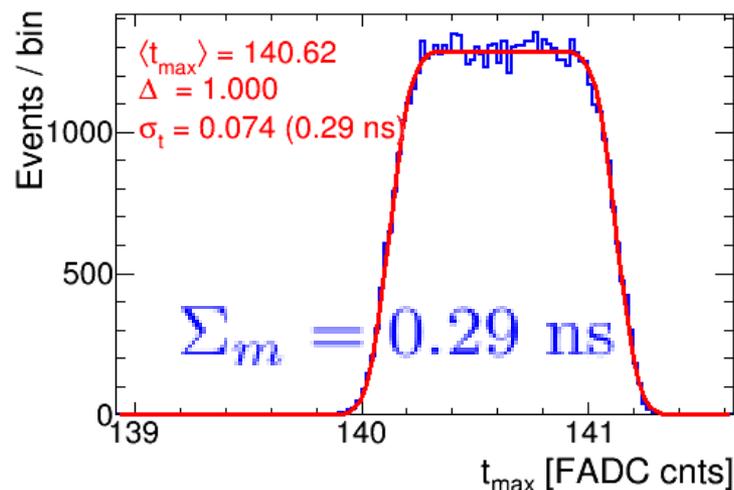
Run 214. Am



- Result of the fit depends on slewing correction in trigger time and correlation between trigger and signal time
- It may be use for a rough estimate of time resolution but not for a precise measurement

Experimental evaluation of time resolution using “software trigger”

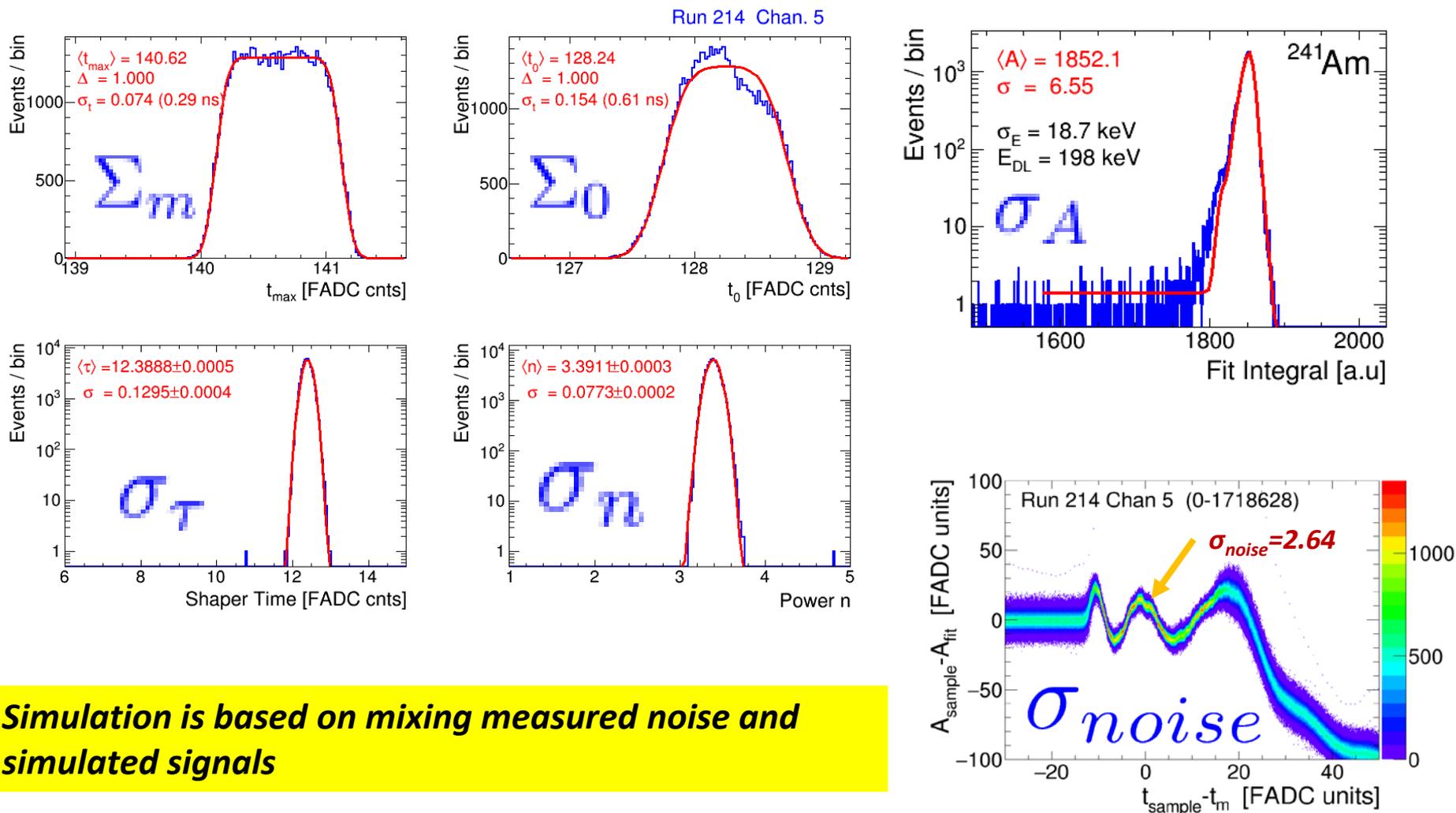
- On previous page, the external trigger was employed only to align samples in different event.
- We can do the same using data offline analysis . Some uncertainties may be eliminated in such a way.
- I found it to be convenient to employ maximum amplitude sample to align all triggers.



$$\Sigma_m = \langle \delta_{tm}^2 \rangle^{1/2} \oplus \sigma_{\text{peak sel.}}$$

Depends only on noise at the peak and, thus, may be simulated.

Parameters used to tune the simulation



Simulation is based on mixing measured noise and simulated signals

Simulation of the Am signal (A=1852)

		Simulation					
	Run 214	1.000	X	X	X	X	shape correction
		0.000	0.000	0.000	0.065	0.02	noise factor
		0.000	0.000	0.000	0.039	0.01	σ_τ (waveform fluctuations)
							σ_n (waveform fluctuations)
Σ_0	0.61 ns	0.47 ns	0.49 ns	0.58 ns	0.57 ns	0.58 ns	
Σ_m	0.29 ns	0.21 ns	0.23 ns	0.28 ns	0.23 ns	0.26 ns	
σ_τ	0.130	0.105	0.109	0.130	0.130 ns	0.129	
σ_n	0.077	0.062	0.065	0.077	0.077 ns	0.077	
σ_A	6.55	4.73	4.80	5.76	16.97	7.25	
σ_{noise}	2.64	2.13	2.53	2.90	2.55	2.85	
σ_{t_0}		0.372 ns	0.392 ns	0.468 ns	0.395 ns	0.460 ns	
σ_{t_m}		0.088 ns	0.088 ns	0.103 ns	0.276 ns	0.130 ns	

For Americium:

Time resolution: $100 \text{ ps} < \sigma_{t_m} < 130 \text{ ps}$

Noise contribution $\sim 100 \text{ ps}$

Waveform fluctuations: $< 80 \text{ ps}$

- The main source of uncertainties is fluctuation of the waveform shape
- t_m should be used for time measurements